

<b>Notice of References Cited</b>	Application/Control No. 09/786,990		Applicant(s)/Patent Under Reexamination ONISHI ET AL.	
	Examiner DEVONA E. FAULK		Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,282,296	08-2001	Konno et al.	381/96
*	B	US-6,122,385	09-2000	Konno et al.	381/96
*	C	US-6,944,302	09-2005	Onishi et al.	381/59
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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